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#### Details

Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	40MHz
Connectivity	I²C, LINbus, SCI, SPI
Peripherals	LVD, POR, PWM, WDT
Number of I/O	13
Program Memory Size	4KB (4K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	256 x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	16-TSSOP (0.173", 4.40mm Width)
Supplier Device Package	16-TSSOP
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s08sh4ctg

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# Chapter 2 Pins and Connections

This section describes signals that connect to package pins. It includes pinout diagrams, recommended system connections, and detailed discussions of signals.

# 2.1 Device Pin Assignment

Figure 2-1 - Figure 2-4 shows the pin assignments for the MC9S08SH8 devices.



Figure 2-1. 24-Pin QFN

MC9S08SH8 MCU Series Data Sheet, Rev. 3



#### **Chapter 2 Pins and Connections**

When an on-chip peripheral system is controlling a pin, data direction control bits still determine what is read from port data registers even though the peripheral module controls the pin direction by controlling the enable for the pin's output buffer. For information about controlling these pins as general-purpose I/O pins, see Chapter 6, "Parallel Input/Output Control."

The MC9S08SH8 devices contain a ganged output drive feature that allows a safe and reliable method of allowing pins to be tied together externally to produce a higher output current drive. See Section 6.3, "Ganged Output" for more information for configuring the port pins for ganged output drive.

#### NOTE

To avoid extra current drain from floating input pins, the reset initialization routine in the application program should either enable on-chip pull-up devices or change the direction of unused pins to outputs so they do not float.

When using the 8-pin devices, the user must either enable on-chip pullup devices or change the direction of non-bonded out port B and port C pins to outputs so the pins do not float.

When using the 16-pin devices, the user must either enable on-chip pullup devices or change the direction of non-bonded out port C pins to outputs so the pins do not float.



**Chapter 4 Memory** 

Address	Register Name	Bit 7	6	5	4	3	2	1	Bit 0	
0x00 <b>68</b>	TPM2C1SC	CH1F	CH1IE	MS1B	MS1A	ELS1B	ELS1A	0	0	
0x00 <b>69</b>	TPM2C1VH	Bit 15	14	13	12	11	10	9	Bit 8	
0x00 <b>6A</b>	TPM2C1VL	Bit 7	6	5	4	3	2	1	Bit 0	
0x00 <b>6B</b>	Reserved	—		_		_	_		_	
0x00 <b>6C</b>	RTCSC	RTIF	RTC	LKS	RTIE	RTCPS				
0x00 <b>6D</b>	RTCCNT		RTCCNT							
0x00 <b>6E</b>	RTCMOD		RTCMOD							
0x00 <b>6F -</b> 0x00 <b>7F</b>	Reserved	_	_	_	_	_	_			

### Table 4-2. Direct-Page Register Summary (Sheet 3 of 3)



f <sub>Bus</sub>	PRDIV8 (Binary)	DIV (Decimal)	f <sub>FCLK</sub>	Program/Erase Timing Pulse (5 μs Min, 6.7 μs Max)
20 MHz	1	12	192.3 kHz	5.2 μs
10 MHz	0	49	200 kHz	5 μs
8 MHz	0	39	200 kHz	5 μs
4 MHz	0	19	200 kHz	5 μs
2 MHz	0	9	200 kHz	5 μs
1 MHz	0	4	200 kHz	5 μs
200 kHz	0	0	200 kHz	5 μs
150 kHz	0	0	150 kHz	6.7 μs

# 4.7.2 FLASH Options Register (FOPT and NVOPT)

During reset, the contents of the nonvolatile location NVOPT are copied from FLASH into FOPT. To change the value in this register, erase and reprogram the NVOPT location in FLASH memory as usual and then issue a new MCU reset.



= Unimplemented or Reserved

#### Figure 4-6. FLASH Options Register (FOPT)

#### Table 4-8. FOPT Register Field Descriptions

Field	Description
7 KEYEN	<ul> <li>Backdoor Key Mechanism Enable — When this bit is 0, the backdoor key mechanism cannot be used to disengage security. The backdoor key mechanism is accessible only from user (secured) firmware. BDM commands cannot be used to write key comparison values that would unlock the backdoor key. For more detailed information about the backdoor key mechanism, refer to Section 4.6, "Security."</li> <li>No backdoor key access allowed.</li> <li>If user firmware writes an 8-byte value that matches the nonvolatile backdoor key (NVBACKKEY through NVBACKKEY+7 in that order), security is temporarily disengaged until the next MCU reset.</li> </ul>
6 FNORED	<ul> <li>Vector Redirection Disable — When this bit is 1, then vector redirection is disabled.</li> <li>0 Vector redirection enabled.</li> <li>1 Vector redirection disabled.</li> </ul>
1:0 SEC0[1:0]	Security State Code — This 2-bit field determines the security state of the MCU as shown in Table 4-9. When the MCU is secure, the contents of RAM and FLASH memory cannot be accessed by instructions from any unsecured source including the background debug interface. SEC01:SEC00 changes to 1:0 after successful backdoor key entry or a successful blank check of FLASH. For more detailed information about security, refer to Section 4.6, "Security."



# 6.3 Ganged Output

The MC9S08SH8 devices contain a feature that allows for up to eight port pins to be tied together externally to allow higher output current drive. The ganged output drive control register (GNGC) is a write-once register that is used to enabled the ganged output feature and select which port pins will be used as ganged outputs. The GNGEN bit in GNGC enables ganged output. The GNGPS[7:1] bits are used to select which pin will be part of the ganged output.

When GNGEN is set, any pin that is enabled as a ganged output will be automatically configured as an output and follow the data, drive strength and slew rate control of PTC0. The ganged output drive pin mapping is shown in Table 6-1.

#### NOTE

See the DC characteristics in the electrical section for maximum Port I/O currents allowed for this MCU.

When a pin is enabled as ganged output, this feature will have priority over any digital module. An enabled analog function will have priority over the ganged output pin. See Table 2-1 for information on pin priority.

	GNGC Register Bits								
	GNGPS7	GNGPS7 GNGPS6 GNGPS5 GNGPS4 GNGPS3 GNGPS2 GNGPS1 GNGE							
Port Pin <sup>2</sup>	PTB5	PTB4	PTB3	PTB2	PTC3	PTC2	PTC1	PTC0	
Data Direction Control		Pin is automatically configured as output when pin is enabled as ganged output.							
Data Control		PTCD0 in PTCD controls data value of output							
Drive Strength Control		PTCDS0 in PTCDS controls drive stength of output							
Slew Rate Control		PTCSE0 in PTCSE controls slew rate of output							

Table 6-1.	Ganged	Output	Pin	Enable
	<u> </u>			

<sup>1</sup> Ganged output not available on 8-pin packages. PTC3-PTC0 not available on 16-pin packages, however PTC0 control registers are still used to control ganged output.

<sup>2</sup> When GNGEN = 1, PTC0 is forced to an output, regardless of the value in PTCDD0 in PTCDD.



Chapter 6 Parallel Input/Output Control

# 6.6.1.4 Port A Slew Rate Enable Register (PTASE)



#### Figure 6-6. Slew Rate Enable for Port A Register (PTASE)

#### Table 6-5. PTASE Register Field Descriptions

Field	Description
5 Reserved	<b>Reserved Bits</b> — These bits are unused on this MCU, writes have no affect and could read as 1s or 0s.
4:0 PTASE[4:0]	<ul> <li>Output Slew Rate Enable for Port A Bits — Each of these control bits determines if the output slew rate control is enabled for the associated PTA pin. For port A pins that are configured as inputs, these bits have no effect.</li> <li>Output slew rate control disabled for port A bit n.</li> <li>Output slew rate control enabled for port A bit n.</li> </ul>

# 6.6.1.5 Port A Drive Strength Selection Register (PTADS)

	7	6	5	4	3	2	1	0
R	0	0	P	ρτάροα				
w			ĸ	F IAD34	F IAD33	F IAD32	FIADST	F IAD30
Reset:	0	0	0	0	0	0	0	0

#### Figure 6-7. Drive Strength Selection for Port A Register (PTADS)

#### Table 6-6. PTADS Register Field Descriptions

Field	Description
5 Reserved	<b>Reserved Bits</b> — These bits are unused on this MCU, writes have no affect and could read as 1s or 0s.
4:0 PTADS[4:0]	<ul> <li>Output Drive Strength Selection for Port A Bits — Each of these control bits selects between low and high output drive for the associated PTA pin. For port A pins that are configured as inputs, these bits have no effect.</li> <li>0 Low output drive strength selected for port A bit n.</li> <li>1 High output drive strength selected for port A bit n.</li> </ul>





### 7.3.6.7 SP-Relative, 16-Bit Offset (SP2)

This variation of indexed addressing uses the 16-bit value in the stack pointer (SP) plus a 16-bit offset included in the instruction as the address of the operand needed to complete the instruction.

# 7.4 Special Operations

The CPU performs a few special operations that are similar to instructions but do not have opcodes like other CPU instructions. In addition, a few instructions such as STOP and WAIT directly affect other MCU circuitry. This section provides additional information about these operations.

# 7.4.1 Reset Sequence

Reset can be caused by a power-on-reset (POR) event, internal conditions such as the COP (computer operating properly) watchdog, or by assertion of an external active-low reset pin. When a reset event occurs, the CPU immediately stops whatever it is doing (the MCU does not wait for an instruction boundary before responding to a reset event). For a more detailed discussion about how the MCU recognizes resets and determines the source, refer to the Resets, Interrupts, and System Configuration chapter.

The reset event is considered concluded when the sequence to determine whether the reset came from an internal source is done and when the reset pin is no longer asserted. At the conclusion of a reset event, the CPU performs a 6-cycle sequence to fetch the reset vector from 0xFFFE and 0xFFFF and to fill the instruction queue in preparation for execution of the first program instruction.

# 7.4.2 Interrupt Sequence

When an interrupt is requested, the CPU completes the current instruction before responding to the interrupt. At this point, the program counter is pointing at the start of the next instruction, which is where the CPU should return after servicing the interrupt. The CPU responds to an interrupt by performing the same sequence of operations as for a software interrupt (SWI) instruction, except the address used for the vector fetch is determined by the highest priority interrupt that is pending when the interrupt sequence started.

The CPU sequence for an interrupt is:

- 1. Store the contents of PCL, PCH, X, A, and CCR on the stack, in that order.
- 2. Set the I bit in the CCR.
- 3. Fetch the high-order half of the interrupt vector.
- 4. Fetch the low-order half of the interrupt vector.
- 5. Delay for one free bus cycle.
- 6. Fetch three bytes of program information starting at the address indicated by the interrupt vector to fill the instruction queue in preparation for execution of the first instruction in the interrupt service routine.

After the CCR contents are pushed onto the stack, the I bit in the CCR is set to prevent other interrupts while in the interrupt service routine. Although it is possible to clear the I bit with an instruction in the



#### Chapter 7 Central Processor Unit (S08CPUV2)

Source	Operation	dress lode	Object Code	/cles	Cyc-by-Cyc	Affect on CCR	
		Ρq Ad		ΰ	Details	<b>V</b> 1 1 <b>H</b>	INZC
BPL rel	Branch if Plus (if N = 0)	REL	2A rr	3	ppp	- 1 1 -	
BRA rel	Branch Always (if I = 1)	REL	20 rr	3	ppp	- 1 1 -	
BRCLR n,opr8a,rel	Branch if Bit <i>n</i> in Memory Clear (if (Mn) = 0)	DIR (b0) DIR (b1) DIR (b2) DIR (b3) DIR (b3) DIR (b4) DIR (b5) DIR (b6) DIR (b7)	01 dd rr 03 dd rr 05 dd rr 07 dd rr 09 dd rr 0B dd rr 0D dd rr 0F dd rr	5 5 5 5 5 5 5 5 5	rpppp rpppp rpppp rpppp rpppp rpppp	- 1 1 -	\$
BRN rel	Branch Never (if I = 0)	REL	21 rr	3	qqq	- 1 1 -	
BRSET n,opr8a,rel	Branch if Bit <i>n</i> in Memory Set (if (Mn) = 1)	DIR (b0) DIR (b1) DIR (b2) DIR (b3) DIR (b3) DIR (b4) DIR (b5) DIR (b6) DIR (b7)	00 dd rr 02 dd rr 04 dd rr 06 dd rr 08 dd rr 0A dd rr 0C dd rr 0E dd rr	5 5 5 5 5 5 5 5 5	трррр грррр грррр грррр грррр грррр	- 1 1 -	\$
BSET n,opr8a	Set Bit <i>n</i> in Memory (Mn ← 1)	DIR (b0) DIR (b1) DIR (b2) DIR (b3) DIR (b3) DIR (b4) DIR (b5) DIR (b6) DIR (b7)	10 dd 12 dd 14 dd 16 dd 18 dd 1A dd 1C dd 1E dd	5 5 5 5 5 5 5 5 5 5 5	rfwpp rfwpp rfwpp rfwpp rfwpp rfwpp rfwpp rfwpp rfwpp	- 1 1 -	
BSR rel	$\begin{array}{l} \text{Branch to Subroutine} \\ \text{PC} \leftarrow (\text{PC}) + \$0002 \\ \text{push (PCL); SP} \leftarrow (\text{SP}) - \$0001 \\ \text{push (PCH); SP} \leftarrow (\text{SP}) - \$0001 \\ \text{PC} \leftarrow (\text{PC}) + rel \end{array}$	REL	AD rr	5	qqqaa	- 1 1 -	
CBEQ opr8a,rel CBEQA #opr8i,rel CBEQX #opr8i,rel CBEQ oprx8,X+,rel CBEQ ,X+,rel CBEQ oprx8,SP,rel	Compare and Branch if $(A) = (M)$ Branch if $(A) = (M)$ Branch if $(X) = (M)$ Branch if $(A) = (M)$ Branch if $(A) = (M)$ Branch if $(A) = (M)$	DIR IMM IX1+ IX+ SP1	31 dd rr 41 ii rr 51 ii rr 61 ff rr 71 rr 9E 61 ff rr	5 4 5 5 6	rpppp pppp pppp rpppp rfppp prpppp	- 1 1 -	
CLC	Clear Carry Bit (C $\leftarrow$ 0)	INH	98	1	q	- 1 1 -	0
CLI	Clear Interrupt Mask Bit (I $\leftarrow$ 0)	INH	9A	1	p	- 1 1 -	0
CLR opr8a CLRA CLRX CLRH CLR oprx8,X CLR ,X CLR oprx8,SP	Clear $M \leftarrow \$00$ $A \leftarrow \$00$ $X \leftarrow \$00$ $H \leftarrow \$00$ $M \leftarrow \$00$ $M \leftarrow \$00$ $M \leftarrow \$00$	DIR INH INH INH IX1 IX SP1	3F dd 4F 5F 8C 6F ff 7F 9E 6F ff	5 1 1 5 4 6	rfwpp p p rfwpp rfwp prfwpp	011-	- 0 1 -

#### Table 7-2. Instruction Set Summary (Sheet 3 of 9)



Chapter 8 Analog Comparator (S08ACMPV2)

# 8.3.1.1 ACMP Status and Control Register (ACMPSC)

ACMPSC contains the status flag and control bits which are used to enable and configure the ACMP.



#### Figure 8-3. ACMP Status and Control Register

Field	Description
7 ACME	<ul> <li>Analog Comparator Module Enable — ACME enables the ACMP module.</li> <li>0 ACMP not enabled</li> <li>1 ACMP is enabled</li> </ul>
6 ACBGS	<ul> <li>Analog Comparator Bandgap Select — ACBGS is used to select between the bandgap reference voltage or the ACMP+ pin as the input to the non-inverting input of the analog comparatorr.</li> <li>0 External pin ACMP+ selected as non-inverting input to comparator</li> <li>1 Internal reference select as non-inverting input to comparator</li> <li>Note: refer to this chapter introduction to verify if any other config bits are necessary to enable the bandgap reference in the chip level.</li> </ul>
5 ACF	<ul> <li>Analog Comparator Flag — ACF is set when a compare event occurs. Compare events are defined by ACMOD.</li> <li>ACF is cleared by writing a one to ACF.</li> <li>0 Compare event has not occured</li> <li>1 Compare event has occured</li> </ul>
4 ACIE	<ul> <li>Analog Comparator Interrupt Enable — ACIE enables the interrupt from the ACMP. When ACIE is set, an interupt will be asserted when ACF is set.</li> <li>0 Interrupt disabled</li> <li>1 Interrupt enabled</li> </ul>
3 ACO	<b>Analog Comparator Output</b> — Reading ACO will return the current value of the analog comparator output. ACO is reset to a 0 and will read as a 0 when the ACMP is disabled (ACME = 0).
2 ACOPE	<ul> <li>Analog Comparator Output Pin Enable — ACOPE is used to enable the comparator output to be placed onto the external pin, ACMPO.</li> <li>0 Analog comparator output not available on ACMPO</li> <li>1 Analog comparator output is driven out on ACMPO</li> </ul>
1:0 ACMOD	Analog Comparator Mode — ACMOD selects the type of compare event which sets ACF.         00 Encoding 0 — Comparator output falling edge         01 Encoding 1 — Comparator output rising edge         10 Encoding 2 — Comparator output falling edge         11 Encoding 3 — Comparator output rising or falling edge

#### Table 8-2. ACMP Status and Control Register Field Descriptions

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Chapter 9 Analog-to-Digital Converter (S08ADC10V1)

# 9.4.4.2 Completing Conversions

A conversion is completed when the result of the conversion is transferred into the data result registers, ADCRH and ADCRL. This is indicated by the setting of COCO. An interrupt is generated if AIEN is high at the time that COCO is set.

A blocking mechanism prevents a new result from overwriting previous data in ADCRH and ADCRL if the previous data is in the process of being read while in 10-bit MODE (the ADCRH register has been read but the ADCRL register has not). When blocking is active, the data transfer is blocked, COCO is not set, and the new result is lost. In the case of single conversions with the compare function enabled and the compare condition false, blocking has no effect and ADC operation is terminated. In all other cases of operation, when a data transfer is blocked, another conversion is initiated regardless of the state of ADCO (single or continuous conversions enabled).

If single conversions are enabled, the blocking mechanism could result in several discarded conversions and excess power consumption. To avoid this issue, the data registers must not be read after initiating a single conversion until the conversion completes.

# 9.4.4.3 Aborting Conversions

Any conversion in progress will be aborted when:

- A write to ADCSC1 occurs (the current conversion will be aborted and a new conversion will be initiated, if ADCH are not all 1s).
- A write to ADCSC2, ADCCFG, ADCCVH, or ADCCVL occurs. This indicates a mode of operation change has occurred and the current conversion is therefore invalid.
- The MCU is reset.
- The MCU enters stop mode with ADACK not enabled.

When a conversion is aborted, the contents of the data registers, ADCRH and ADCRL, are not altered but continue to be the values transferred after the completion of the last successful conversion. In the case that the conversion was aborted by a reset, ADCRH and ADCRL return to their reset states.

# 9.4.4.4 Power Control

The ADC module remains in its idle state until a conversion is initiated. If ADACK is selected as the conversion clock source, the ADACK clock generator is also enabled.

Power consumption when active can be reduced by setting ADLPC. This results in a lower maximum value for  $f_{ADCK}$  (see the electrical specifications).

# 9.4.4.5 Total Conversion Time

The total conversion time depends on the sample time (as determined by ADLSMP), the MCU bus frequency, the conversion mode (8-bit or 10-bit), and the frequency of the conversion clock ( $f_{ADCK}$ ). After the module becomes active, sampling of the input begins. ADLSMP is used to select between short and long sample times. When sampling is complete, the converter is isolated from the input channel and a successive approximation algorithm is performed to determine the digital value of the analog signal. The



Chapter 9 Analog-to-Digital Converter (S08ADC10V1)

# 9.4.5 Automatic Compare Function

The compare function can be configured to check for either an upper limit or lower limit. After the input is sampled and converted, the result is added to the two's complement of the compare value (ADCCVH and ADCCVL). When comparing to an upper limit (ACFGT = 1), if the result is greater-than or equal-to the compare value, COCO is set. When comparing to a lower limit (ACFGT = 0), if the result is less than the compare value, COCO is set. The value generated by the addition of the conversion result and the two's complement of the compare value is transferred to ADCRH and ADCRL.

Upon completion of a conversion while the compare function is enabled, if the compare condition is not true, COCO is not set and no data is transferred to the result registers. An ADC interrupt is generated upon the setting of COCO if the ADC interrupt is enabled (AIEN = 1).

### NOTE

The compare function can be used to monitor the voltage on a channel while the MCU is in either wait or stop3 mode. The ADC interrupt will wake the MCU when the compare condition is met.

# 9.4.6 MCU Wait Mode Operation

The WAIT instruction puts the MCU in a lower power-consumption standby mode from which recovery is very fast because the clock sources remain active. If a conversion is in progress when the MCU enters wait mode, it continues until completion. Conversions can be initiated while the MCU is in wait mode by means of the hardware trigger or if continuous conversions are enabled.

The bus clock, bus clock divided by two, and ADACK are available as conversion clock sources while in wait mode. The use of ALTCLK as the conversion clock source in wait is dependent on the definition of ALTCLK for this MCU. Consult the module introduction for information on ALTCLK specific to this MCU.

A conversion complete event sets the COCO and generates an ADC interrupt to wake the MCU from wait mode if the ADC interrupt is enabled (AIEN = 1).

# 9.4.7 MCU Stop3 Mode Operation

The STOP instruction is used to put the MCU in a low power-consumption standby mode during which most or all clock sources on the MCU are disabled.

# 9.4.7.1 Stop3 Mode With ADACK Disabled

If the asynchronous clock, ADACK, is not selected as the conversion clock, executing a STOP instruction aborts the current conversion and places the ADC in its idle state. The contents of ADCRH and ADCRL are unaffected by stop3 mode. After exiting from stop3 mode, a software or hardware trigger is required to resume conversions.



# 9.6.2 Sources of Error

Several sources of error exist for A/D conversions. These are discussed in the following sections.

### 9.6.2.1 Sampling Error

For proper conversions, the input must be sampled long enough to achieve the proper accuracy. Given the maximum input resistance of approximately  $7k\Omega$  and input capacitance of approximately 5.5 pF, sampling to within 1/4LSB (at 10-bit resolution) can be achieved within the minimum sample window (3.5 cycles @ 8 MHz maximum ADCK frequency) provided the resistance of the external analog source ( $R_{AS}$ ) is kept below 5 k $\Omega$ .

Higher source resistances or higher-accuracy sampling is possible by setting ADLSMP (to increase the sample window to 23.5 cycles) or decreasing ADCK frequency to increase sample time.

### 9.6.2.2 Pin Leakage Error

Leakage on the I/O pins can cause conversion error if the external analog source resistance ( $R_{AS}$ ) is high. If this error cannot be tolerated by the application, keep  $R_{AS}$  lower than  $V_{DDAD} / (2^{N*}I_{LEAK})$  for less than 1/4LSB leakage error (N = 8 in 8-bit mode or 10 in 10-bit mode).

### 9.6.2.3 Noise-Induced Errors

System noise which occurs during the sample or conversion process can affect the accuracy of the conversion. The ADC accuracy numbers are guaranteed as specified only if the following conditions are met:

- There is a 0.1  $\mu$ F low-ESR capacitor from V<sub>REFH</sub> to V<sub>REFL</sub>.
- There is a 0.1  $\mu$ F low-ESR capacitor from V<sub>DDAD</sub> to V<sub>SSAD</sub>.
- If inductive isolation is used from the primary supply, an additional 1  $\mu$ F capacitor is placed from V<sub>DDAD</sub> to V<sub>SSAD</sub>.
- $V_{SSAD}$  (and  $V_{REFL}$ , if connected) is connected to  $V_{SS}$  at a quiet point in the ground plane.
- Operate the MCU in wait or stop3 mode before initiating (hardware triggered conversions) or immediately after initiating (hardware or software triggered conversions) the ADC conversion.
  - For software triggered conversions, immediately follow the write to the ADCSC1 with a WAIT instruction or STOP instruction.
  - For stop3 mode operation, select ADACK as the clock source. Operation in stop3 reduces V<sub>DD</sub> noise but increases effective conversion time due to stop recovery.
- There is no I/O switching, input or output, on the MCU during the conversion.

There are some situations where external system activity causes radiated or conducted noise emissions or excessive  $V_{DD}$  noise is coupled into the ADC. In these situations, or when the MCU cannot be placed in wait or stop3 or I/O activity cannot be halted, these recommended actions may reduce the effect of noise on the accuracy:

• Place a 0.01  $\mu$ F capacitor (C<sub>AS</sub>) on the selected input channel to V<sub>REFL</sub> or V<sub>SSAD</sub> (this will improve noise issues but will affect sample rate based on the external analog source resistance).



Field	Description
1	<b>OSC Initialization</b> — If the external reference clock is selected by ERCLKEN or by the ICS being in FEE, FBE, or FBELP mode, and if EREFS is set, then this bit is set after the initialization cycles of the external oscillator clock have completed. This bit is only cleared when either ERCLKEN or EREFS are cleared.
0	<b>ICS Fine Trim</b> — The FTRIM bit controls the smallest adjustment of the internal reference clock frequency. Setting FTRIM will increase the period and clearing FTRIM will decrease the period by the smallest amount possible.

Table 10-5. ICS Status and Control Register Field Descriptions (continued)

# 10.4 Functional Description

### **10.4.1 Operational Modes**



Figure 10-7. Clock Switching Modes

The seven states of the ICS are shown as a state diagram and are described below. The arrows indicate the allowed movements between the states.

# 10.4.1.1 FLL Engaged Internal (FEI)

FLL engaged internal (FEI) is the default mode of operation and is entered when all the following conditions occur:





### 11.1.2 Features

The IIC includes these distinctive features:

- Compatible with IIC bus standard
- Multi-master operation
- Software programmable for one of 64 different serial clock frequencies
- Software selectable acknowledge bit
- Interrupt driven byte-by-byte data transfer
- Arbitration lost interrupt with automatic mode switching from master to slave
- Calling address identification interrupt
- Start and stop signal generation/detection
- Repeated start signal generation
- Acknowledge bit generation/detection
- Bus busy detection
- General call recognition
- 10-bit address extension

# 11.1.3 Modes of Operation

A brief description of the IIC in the various MCU modes is given here.

- **Run mode** This is the basic mode of operation. To conserve power in this mode, disable the module.
- **Wait mode** The module continues to operate while the MCU is in wait mode and can provide a wake-up interrupt.
- **Stop mode** The IIC is inactive in stop3 mode for reduced power consumption. The stop instruction does not affect IIC register states. Stop2 resets the register contents.



Arbitration is lost in the following circumstances:

- SDA sampled as a low when the master drives a high during an address or data transmit cycle.
- SDA sampled as a low when the master drives a high during the acknowledge bit of a data receive cycle.
- A start cycle is attempted when the bus is busy.
- A repeated start cycle is requested in slave mode.
- A stop condition is detected when the master did not request it.

This bit must be cleared by software writing a 1 to it.



#### Table 15-7. SPIS Register Field Descriptions

Field	Description
7 SPRF	<ul> <li>SPI Read Buffer Full Flag — SPRF is set at the completion of an SPI transfer to indicate that received data may be read from the SPI data register (SPID). SPRF is cleared by reading SPRF while it is set, then reading the SPI data register.</li> <li>No data available in the receive data buffer</li> <li>Data available in the receive data buffer</li> </ul>
5 SPTEF	SPI Transmit Buffer Empty Flag — This bit is set when there is room in the transmit data buffer. It is cleared by reading SPIS with SPTEF set, followed by writing a data value to the transmit buffer at SPID. SPIS must be read with SPTEF = 1 before writing data to SPID or the SPID write will be ignored. SPTEF generates an SPTEF CPU interrupt request if the SPTIE bit in the SPIC1 is also set. SPTEF is automatically set when a data byte transfers from the transmit buffer into the transmit shift register. For an idle SPI (no data in the transmit buffer or the shift register and no transfer in progress), data written to SPID is transferred to the shifter almost immediately so SPTEF is set within two bus cycles allowing a second 8-bit data value to be queued into the transmit buffer. After completion of the transfer of the value in the shift register, the queued value from the transmit buffer will automatically move to the shifter and SPTEF will be set to indicate there is room for new data in the transmit buffer not empty.
4 MODF	Master Mode Fault Flag — MODF is set if the SPI is configured as a master and the slave select input goes low, indicating some other SPI device is also configured as a master. The SS pin acts as a mode fault error input only when MSTR = 1, MODFEN = 1, and SSOE = 0; otherwise, MODF will never be set. MODF is cleared by reading MODF while it is 1, then writing to SPI control register 1 (SPIC1). 0 No mode fault error 1 Mode fault error detected

# 15.4.5 SPI Data Register (SPID)

	7	6	5	4	3	2	1	0
R W	Bit 7	6	5	4	3	2	1	Bit 0
Reset	0	0	0	0	0	0	0	0

Figure 15-9. SPI Data Register (SPID)

Reads of this register return the data read from the receive data buffer. Writes to this register write data to the transmit data buffer. When the SPI is configured as a master, writing data to the transmit data buffer initiates an SPI transfer.

Data should not be written to the transmit data buffer unless the SPI transmit buffer empty flag (SPTEF) is set, indicating there is room in the transmit buffer to queue a new transmit byte.

Data may be read from SPID any time after SPRF is set and before another transfer is finished. Failure to read the data out of the receive data buffer before a new transfer ends causes a receive overrun condition and the data from the new transfer is lost.

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Appendix A Electrical Characteristics



Figure A-11. IRQ/Pin Interrupt Timing



Appendix A Electrical Characteristics

# A.14 EMC Performance

Electromagnetic compatibility (EMC) performance is highly dependant on the environment in which the MCU resides. Board design and layout, circuit topology choices, location and characteristics of external components as well as MCU software operation all play a significant role in EMC performance. The system designer should consult Freescale applications notes such as AN2321, AN1050, AN1263, AN2764, and AN1259 for advice and guidance specifically targeted at optimizing EMC performance.

# A.14.1 Radiated Emissions

Microcontroller radiated RF emissions are measured from 150 kHz to 1 GHz using the TEM/GTEM Cell method in accordance with the IEC 61967-2 and SAE J1752/3 standards. The measurement is performed with the microcontroller installed on a custom EMC evaluation board while running specialized EMC test software. The radiated emissions from the microcontroller are measured in a TEM cell in two package orientations (North and East).

The maximum radiated RF emissions of the tested configuration in all orientations are less than or equal to the reported emissions levels.

Parameter	Symbol	Conditions	Frequency	f <sub>OSC</sub> /f <sub>BUS</sub>	Level <sup>1</sup> (Max)	Unit
	V <sub>RE_TEM</sub>	$V_{DD} = 5 V$ $T_A = +25^{\circ}C$ package type 16-TSSOP	0.15 – 50 MHz	4 MHz crystal 16 MHzbus	0	dBμV
			50 – 150 MHz		0	
Radiated emissions,			150 – 500 MHz		-6	
electric field			500 – 1000 MHz		-9	
			IEC Level		Ν	_
			SAE Level		1	_

Table A-17. Radiated Emissions, Electric Field

<sup>1</sup> Data based on qualification test results.

# A.14.2 Conducted Transient Susceptibility

Microcontroller transient conducted susceptibility is measured in accordance with an internal Freescale test method. The measurement is performed with the microcontroller installed on a custom EMC evaluation board and running specialized EMC test software designed in compliance with the test method. The conducted susceptibility is determined by injecting the transient susceptibility signal on each pin of the microcontroller. The transient waveform and injection methodology is based on IEC 61000-4-4 (EFT/B). The transient voltage required to cause performance degradation on any pin in the tested configuration is greater than or equal to the reported levels unless otherwise indicated by footnotes below Table A-18.



NOTES:

- 1. DIMENSIONS ARE IN MILLIMETERS.
- 2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- 3. DATUMS A AND B TO BE DETERMINED AT THE PLANE WHERE THE BOTTOM OF THE LEADS EXIT THE PLASTIC BODY.
- A. THIS DIMENSION DOES NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURRS. MOLD FLASH, PROTRUSION OR GATE BURRS SHALL NOT EXCEED 0.15 MM PER SIDE. THIS DIMENSION IS DETERMINED AT THE PLANE WHERE THE BOTTOM OF THE LEADS EXIT THE PLASTIC BODY.
- 5. THIS DIMENSION DOES NOT INCLUDE INTER-LEAD FLASH OR PROTRUSIONS. INTER-LEAD FLASH AND PROTRUSIONS SHALL NOT EXCEED 0.25 MM PER SIDE. THIS DIMENSION IS DETERMINED AT THE PLANE WHERE THE BOTTOM OF THE LEADS EXIT THE PLASTIC BODY.
- 6. THIS DIMENSION DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL NOT CAUSE THE LEAD WIDTH TO EXCEED 0.62 mm.

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20LD SOIC W/B, 1.2/	PIICH,	CASE NUMBER	: 751D-07	23 MAR 2005
		STANDARD: JE	DEC MS-013AC	







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16 LD TSSOP. PITCH 0	CASE NUMBER: 948F-01 19 MAY 2				
10 LD 10001, 111011 0.	, , , , , , , , , , , , , , , , , , , ,		DEC		